

Search Notes

Application/Control No.

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Examiner

Wen-Ying P. Chen

Applicant(s)/Patent under
Reexamination

YAMASHITA ET AL.

Art Unit

2871

SEARCHED

Class	Subclass	Date	Examiner
349	109,107	10/14/2005	WPC

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
349/106 and key word search in USPGPUB,USPAT,USOCR,EPO,JPO ,DERWENT,IBM_TDB in EAST: see search history printout	10/16/2005	WPC